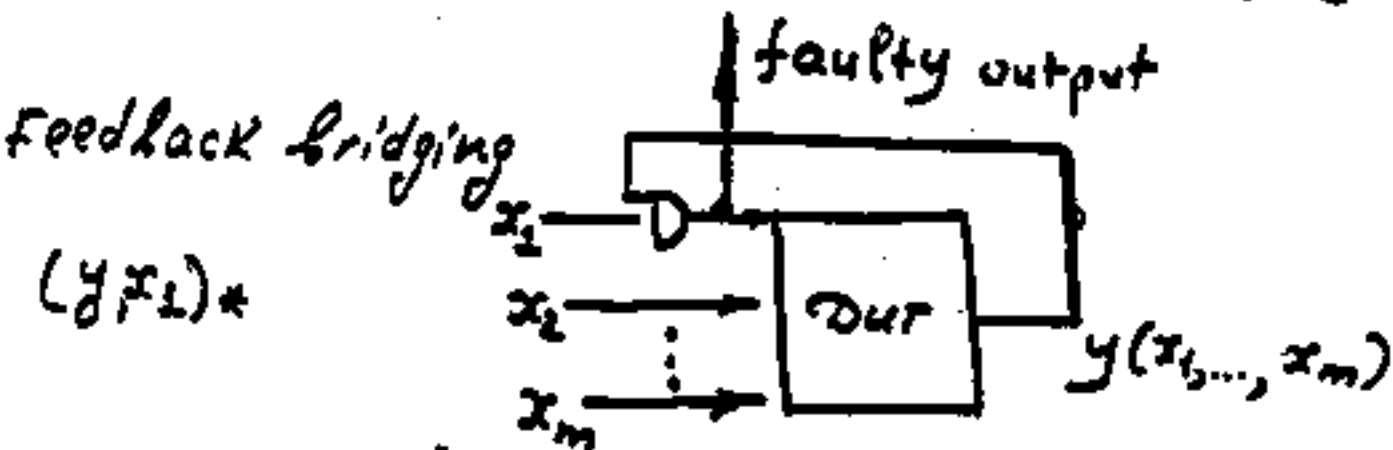
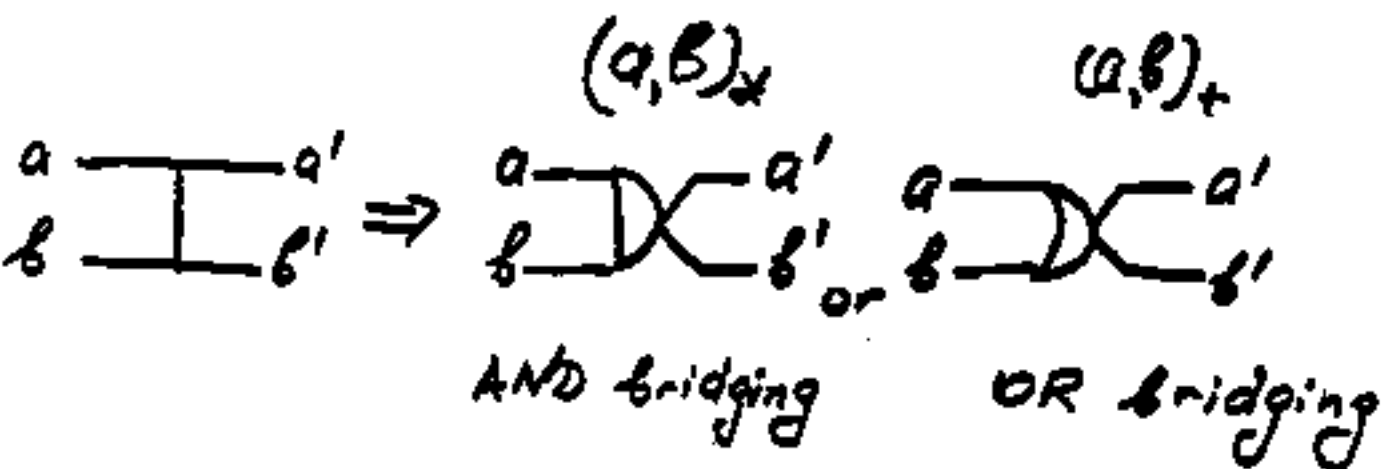


Detection of Bridging Faults

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Fault Models



Detection of Feedback Bridgings

If $f(0, \dots, 0) = 1$, then $(0, \dots, 0)$ detects all $(y, x)_+$
 If $f(1, \dots, 1) = 0$, then $(1, \dots, 1)$ detects all $(y, x)_+$

To detect AND Feedback Bridgings:

1. Apply $a = (a_1, \dots, a_m) : f(a_1, \dots, a_m) = 0$
2. Apply $b = (b_1, \dots, b_m) : f(b_1, \dots, b_m) = 1$ and $\sum_i b_i \rightarrow \min ((b_1, \dots, b_m) \neq 0)$

To detect OR Feedback Bridgings

1. Apply $\tilde{a} = (\tilde{a}_1, \dots, \tilde{a}_m) : f(\tilde{a}_1, \dots, \tilde{a}_m) = 1$
2. Apply $\tilde{b} = (\tilde{b}_1, \dots, \tilde{b}_m) : f(\tilde{b}_1, \dots, \tilde{b}_m) = 0$ and $\sum_i \tilde{b}_i \rightarrow \max$

" \tilde{b} " should be applied after " \tilde{a} "
 To detect all AND and OR bridgings $(x_i, y)_+$ and $(x_i, y)_*$ apply 3 patterns:
 (a. b = \tilde{a}, \tilde{b})

10.3

Example $f(x_1, \dots, x_{12}) = 1$ iff there are
at least 9 ones in an input vector,
 (x_1, \dots, x_{12})

Take $a = (a_1, \dots, a_{12}) = (0, \dots, 0)$

$$b = \tilde{a} = (\underbrace{1, \dots, 1}_9, 0, 0, 0)$$

$$\tilde{b} = (\underbrace{1, \dots, 1}_8, 0, 0, 0, 0)$$

test sequence

$(a = (0, \dots, 0), b = \tilde{a} = (\underbrace{1, \dots, 1}_9, 0, 0, 0),$
 $\tilde{b} = (\underbrace{1, \dots, 1}_8, 0, 0, 0, 0))$ detects

all feedback bridgings $(y, x_i)_*$ and
 $(y, x_i)_+$ ($i = 1, \dots, 12$)

Detection of Nonfeedback Bridgings ^{10.4}

(T_{ij}) - input test matrix \Rightarrow

rows of (T_{ij}) are test patterns

Test T detect all bridgings $(x_i, x_j)_*$

and $(x_i, x_j)_+$ only if columns of (T_{ij})

are different $\Rightarrow T(m) \geq \lceil \log_2(m+2) \rceil$

Example 8-bit adder

$$(T_{ij}) = \begin{pmatrix} 00000000 & 11111111 \\ 00001111 & 00001111 \\ 00110011 & 00110011 \\ 01010101 & 01010101 \end{pmatrix} \begin{matrix} t_1 \\ t_2 \\ t_3 \\ t_4 \end{matrix}$$

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This is the controllability condition

in addition to this we need observability

OUTPUT TEST MATRIX FOR AN

8-bit ADDER

OBSERVABILITY CONDITION

$$\begin{pmatrix} 0 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \\ 0 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 \\ 0 & 0 & 1 & 1 & 0 & 0 & 1 & 1 & 0 \\ 0 & 1 & 0 & 1 & 0 & 1 & 0 & 1 & 0 \end{pmatrix} \begin{matrix} t_1 \\ t_2 \\ t_3 \\ t_4 \end{matrix}$$

↑ s/o not detected ← s/i not detected

All columns are different \Rightarrow
all output bridgings are
detected by (t_1, t_2, t_3, t_4)

this test is optimal since
 $m=16$, $\lceil \log_2 m \rceil = 4$

FOR DETECTION OF INPUT (OUTPUT)
STUCK-AT and BRIDGING FAULTS

NECESSARY CONDITIONS:

- 1) All columns in input (output) test matrices are different (to detect bridgings)
- 2) Every column contains at least one 1 and at least one 0 (to detect stuck-at faults)

For input faults

$$T(m) \geq \lceil \log_2 (m+2) \rceil$$

Minimal Numbers of Test Patterns for¹²⁶

Detection of SSFs and bridgings of I/O
of Standard components

Device	Number of test patterns
1. M-bit shift register with parallel load	$\lceil \log_2(m+2) \rceil + 1$
2. m-bit counter with parallel load	$\lceil \log_2(m+2) \rceil + 1$
3. $m \times 2^m$ decoder/demultiplexer	$2^m + 1$
4. $m \times 1$ multiplexer	$2m$
5. m-bit adder/subtractor	$\lceil \log_2 m \rceil + 3$
6. m-bit multiplier	$2 \lceil \log_2 m \rceil + 2$

(M.G. Karpovsky, S. Su, Proc. 17th Design Automation Conference, pp 494-506, 1980)